

Soonyoung Cha

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/8688136/publications.pdf>

Version: 2024-02-01

9
papers

54
citations

1937685
4
h-index

1872680
6
g-index

9
all docs

9
docs citations

9
times ranked

37
citing authors

#	ARTICLE	IF	CITATIONS
1	System-level variation-aware aging simulator using a unified novel gate-delay model for bias temperature instability, hot carrier injection, and gate oxide breakdown. <i>Microelectronics Reliability</i> , 2015, 55, 1334-1340.	1.7	25
2	Processor-level reliability simulator for time-dependent gate dielectric breakdown. <i>Microprocessors and Microsystems</i> , 2015, 39, 950-960.	2.8	8
3	Negative Bias Temperature Instability and Gate Oxide Breakdown Modeling in Circuits With Die-to-Die Calibration Through Power Supply and Ground Signal Measurements. <i>IEEE Transactions on Very Large Scale Integration (VLSI) Systems</i> , 2017, 25, 2271-2284.	3.1	6
4	Built-in self-test for bias temperature instability, hot-carrier injection, and gate oxide breakdown in embedded DRAMs. <i>Microelectronics Reliability</i> , 2015, 55, 2113-2118.	1.7	5
5	The die-to-die calibrated combined model of negative bias temperature instability and gate oxide breakdown from device to system. <i>Microelectronics Reliability</i> , 2015, 55, 1404-1411.	1.7	4
6	AVERT: An elaborate model for simulating variable retention time in DRAMs. <i>Microelectronics Reliability</i> , 2015, 55, 1313-1319.	1.7	3
7	MBIST and statistical hypothesis test for time dependent dielectric breakdowns due to GOBD vs. BTDDDB in an SRAM array. , 2015, , .		2
8	Design for reliability: A duty-cycle management system for timing violations. , 2016, , .		1
9	Adaptive supply voltage and duty cycle controller for yield-power optimization of ICs. , 2017, , .		0